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INFO	DRMATION TEMENT BY	שפוע	LUSTORE	First Named Inventor	Mark Aaron Behlke	
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	(Use as many sheet	s as ne	cessary)	Examiner Name	Not assigned	
Sheet	1	of	1	Attorney Docket Number	PA2003-4	

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/MS/ /MS/	ВС		WO-99/37717		Lee et al.	07-29-1999		<u> </u>
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		OTHER - NON PATENT LITERATURE DOCUMENTS		lation	
Examiner Doc. Initials No.		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.			
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Examiner Signature	/Mark Staples/	Date Considered	01/03/2008

A concise statement of relevance is being submitted in lieu of a translation. 37 CFR 1.98(a)(3).
 An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).

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Application Number	10/666998	-	_
Filing Date	September 19, 2003		_
First Named Inventor	Andrei Laikhter		_
Group Art Unit	1743		_
Examiner Name	Not assigned		_
Attorney Docket Number	PA2003-4	<del></del>	7

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Examiner Initials	Doc. No.	Application or Patent Number	Kind Code	Name of Patentee or Applicant	Date of Publication	Filing Date If Appropriate
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Examiner Signature	/Mark Staples/	Date Considered	01/03/2008	

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<sup>+</sup> An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).

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Application Number	10/666,998				
Filing Date	9/17/03				
First Named Inventor	Schaadt	l.			
Art Unit	7765 1637				
Examiner Name	Not Yet Assigned Mark Stap	les			
Attorney Docket Number	P117-US .	)			

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Examiner Initials	Cite No. 1 Number - Kind Code <sup>2</sup> (if known	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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1	US- 4.190.488	02-26-1980	Winters, H.F.	
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Not in English

Examiner Signature	/Mark Staples/	Date Considered	01/03/2008

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Application Number	10/666,998	
Filing Date	9/17/03	
First Named Inventor	Schaadt	
Art Unit	<del>1765</del> 1637	
Examiner Name	Norverassioned - Mark Sta	brea
Attorney Docket Number	P117-US	

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Examiner Initials		Document Number Number - Kind Code <sup>2</sup> (if known	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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Application Number	10/666,998			
Filing Date	9/17/03			
First Named Inventor	Schaadt			
Art Unit	1765			
Examiner Name	Not Yet Assigned			
Attorney Docket Number	P117-US			

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Substitute for form 1449B/PTO  INFORMATION DISCLOSURE		Application Number	10/666.998			
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	(use as many s	sheets as ne	cessary)	Examiner Name	NorverAssigned Mark Stapl	.es
Sheet	4	of	6	Attorney Docket Number	P117-US	

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published				
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Examiner	/Mark Staples/	Date	01/03/2008
Signature	man otapiosi	Considered	

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Complete if Known Substitute for form 1449B/PTO 10/666,998 **Application Number** INFORMATION DISCLOSURE 9/17/03 Filing Date STATEMENT BY APPLICANT First Named Inventor Schaadt 1637 1765 - -**Group Art Unit** Not Yet Assigned Mark Staples **Examiner Name** (use as many sheets as necessary) of Attorney Docket Number P117-U\$ Sheet

Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
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Examiner	/Mark Staples/	Date	01/03/2008	
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<sup>1</sup> Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

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Substitute f	or form 1449B/PTO			Complete if Known		
				Application Number	10/666,998	
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ואופן			LIOAII	Group Art Unit	4765 1637	
	(use as many she	ets a	s necessary)	Examiner Name -	-Net Yet Assigned Mark Stapl	e
Sheet	6	of	6	Attorney Docket Number	P117-US	

· .		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS  Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the	T
Examiner Initials	Cite No. <sup>1</sup>	item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	1
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Examiner /Mark Staples/	Date Considered 01/03/2008
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<sup>1</sup> Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449B/PTO				Application Number	10/666,998
INFORMATION DISCLOSURE			OSURE	Filing Date	September 19, 2003
STATE	STATEMENT BY APPLICANT			First Named Inventor	Andrei Laikhter
(use as many sheets as necessary)			2012112	Group Art Unit	1616
			)	Examiner Name	Badio, Barbara P.
Sheet	1	of	1	Attorney Docket Number	013670-9004-US00

	OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS
Example Initials	Interview of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, pages(s), volume-issue numbers(s), publisher, city and/or country where published.
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/MS/	GREENE, T.W. and WUTS, P.G.M., Protective Groups in Organic Synthesis, (1999) 3rd edition John Wiley & Sons, Inc., U.S. (BOOK – NOT PROVIDED)
/MS/	HAUGLAND, R.P. et al., Handbook of Fluorescent Probes and Research Chemicals, (1992) 5 <sup>th</sup> Edition, Molecular Probes, Inc., Oregon, U.S. (BOOK – NOT PROVIDED)
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Signature	/Mark Staples/	Considered	0 1/00.2000

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STATEMENT BY APPLICANT			<b>ICANT</b>	First Named Inventor	Andrei Laikhter	
02				Group Art Unit	1616	
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Sheet	1	of	ı	Attorney Docket Number	013670-9004-US00	

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Examiner Initials	U.S. Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document			
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EP	0272007	Applied Biosystems	June 1988				
wo	91/05060	Applied Biosystems	April 1991				
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	Code	Country Code Foreign Patent Document Number  EP 0272007	Country Code  Foreign Patent Document Name of Patentee or Applicant of Cited Document  EP 0272007 Applied Biosystems	Country Code  Foreign Patent Document Number  Name of Patentee or Applicant of Cited Document  EP  0272007  Applied Biosystems  Date of Publication of Cited Document  Document	Country Code  Foreign Patent Document Number  Name of Patentee or Applicant of Cited Document  EP  0272007  Applied Biosystems  Date of Publication of Cited Document  Translation		

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Substitute for	INFORMATION DISCLOSURE	Complet	Complete if Known			
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	STATEMENT BY APPLICANT	First named Inventor	Andrei Laikhter			
		Group Art Unit	1617			
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	Sheet lof l	Attorney Docket Number	013670-9004-US00			
		J.S. Patent Documents				
Examiner Initials	U.S. Patent Document Number	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document			
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Examiner	/Martin Charles /	Date	01/03/2008	
Signature	/Mark Staples/	Considered	0.1705/2000	

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Complete if Known

Application Number 10/666,998

STATEMENT BY APPLICANT

Filing Date September 19, 2003

First Named Inventor Andrei Laikhter

Group Art Unit 1617

Unknown

013670-9004-00

Examiner Name

Attorney Docket Number

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Application Number		10666998		
Filing Date		2003-09-19		
First Named Inventor	Andı	rei Laikhter		
Art Unit		1637		
Examiner Name Mar		k Staples		
Attorney Docket Number		013670-9004 US00		

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